

Section 5: Drift and Diffusion

Saturday, October 16, 2021 7:44 PM

I. Carrier Concentration Numerical Example

For Silicon,

$$N_c = 2.8 \times 10^{19} \text{ cm}^{-3}$$

$$N_v = 1.04 \times 10^{19} \text{ cm}^{-3}$$

$$E_g = 1.12 \text{ eV}$$

a) What is n_i as a function of temperature?
At $T = 300 \text{ K}$?

b) How does this compare to the atomic density of Silicon?

$$a = 5.43 \text{ \AA}$$

c) What is n, p if $N_D = 10^{17} \text{ cm}^{-3}$?

Where is E_F ? (Assume $T = 300 \text{ K}$).

Take $n_i = 10^{10} \text{ cm}^{-3}$.

d) Suppose $E_F - E_i = -0.3 \text{ eV}$. Is the material n or p type? What is n and p ?

$$a) n_i^2 = N_c N_v e^{-E_g/k_B T}$$

Plugging in the values,

$$n_i^2 = 2.912 \times 10^{38} \times e^{-1.12/k_B T}$$

$$\Rightarrow n_i = 1.706 \times 10^{19} \times e^{-1.12 \text{ eV}/k_B T}$$

With $T=300 \text{ K}$, take $k_B T = 25.9 \text{ meV}$

$$\Rightarrow n_i \approx 6.95 \times 10^9 \text{ cm}^{-3}$$

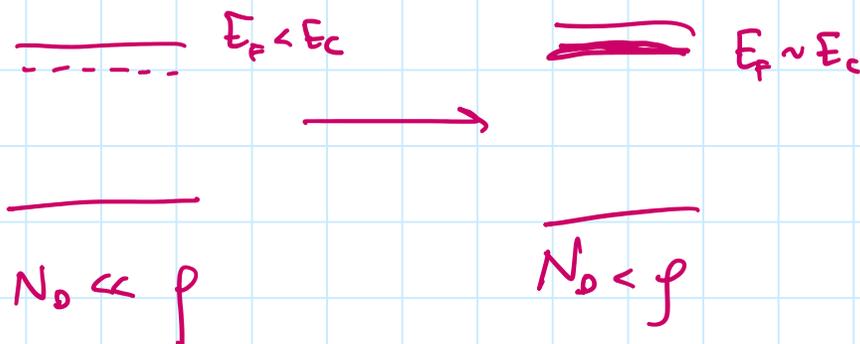
Interestingly, this does not match the oft quoted value of $n_i = 10^{10} \text{ cm}^{-3}$ or $n_i = 1.5 \times 10^{10} \text{ cm}^{-3}$, even in the same textbooks where the values of N_c and N_v I quoted appear. This is an inconsistency which appears to be a result of experimental values of n_i clashing with theoretical calculations of N_c, N_v since Si is not actually that simple of a material. For the purpose of this class though, just take $n_i = 10^{10} \text{ cm}^{-3}$.

b) We can estimate the atomic density of Si to be on the order of

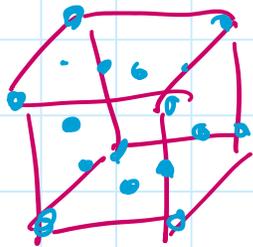
of Si to be on the order of

$$f \sim \frac{1}{a^3} = 6.25 \times 10^{21} \text{ cm}^{-3}$$

Clearly, the intrinsic carrier concentration is basically nothing compared to the total atomic density. It's interesting to consider what happens when the doping level approaches this value — at what point is the material still itself? For Silicon, it is generally accepted that $>10^{19} \text{ cm}^{-3}$ is considered "degenerate doping" and $\sim 10^{20}$ is a realistic upper limit to the doping amount. At this point the defect levels essentially form a continuous band and the Fermi level is roughly at the band edges (usual equations no longer valid).



Actually, because Si is an "fcc" lattice,
 ρ is slightly different



8 corner atoms — each shared w/ 8 cells

6 face-centered atoms — each shared w/ 2 cells

4 internal atoms — each shared w/ 1 cell

$$\Rightarrow 8 \times \frac{1}{8} + 6 \times \frac{1}{2} + 4 = 8 \text{ atoms/cell}$$

$$\therefore \rho = \frac{8 \text{ atoms}}{a^3} \approx 5 \times 10^{22} \text{ cm}^{-3}$$

c) From T: good assumption everything
 is ionized

$$n = N_0 - N_A = N_0 = 10^{17} \text{ cm}^{-3}$$

$$p = n_i^2 / n = 10^{20} / 10^{17} = 10^3 \text{ cm}^{-3}$$

$$n = N_c e^{-(E_c - E_f) / k_B T}$$

$$\Rightarrow E_c - E_f = k_B T \ln \frac{N_c}{n}$$

$$E_f \approx E_c - k_B T \ln \frac{N_c}{n}$$

$$= \dots \dots \dots 2.8 \times 10^9$$

$$\begin{aligned}
 E_F &\approx E_c - k_B T \ln \frac{n}{n_i} \\
 &= E_c - 25.9 \text{ meV} \times \ln \frac{2.8 \times 10^{19}}{10^{17}} \\
 &\approx E_c - 0.146 \text{ eV}
 \end{aligned}$$

$$\begin{aligned}
 \therefore n &= 10^{17} \text{ cm}^{-3} \\
 p &= 10^3 \text{ cm}^{-3} \\
 E_F &= E_c - 0.146 \text{ eV}
 \end{aligned}$$

Alternatively, we can calculate E_F relative to E_i .

$$\begin{aligned}
 n_i &= \sqrt{N_c N_v} e^{-E_g/2k_B T} \\
 &= N_c e^{-(E_c - E_i)/k_B T} \\
 &= N_v e^{-(E_i - E_v)/k_B T} \\
 n &= N_c e^{-(E_c - E_F)/k_B T} \\
 &= N_c e^{-(E_c - E_i + E_i - E_F)/k_B T} \\
 &= N_c e^{-(E_c - E_i)/k_B T} e^{-(E_i - E_F)/k_B T}
 \end{aligned}$$

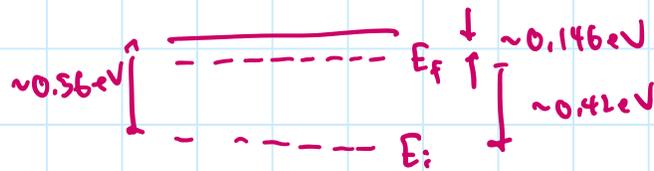
$$\begin{aligned}
 n &= n_i e^{(E_F - E_i)/k_B T} \\
 p &= n_i e^{-(E_F - E_i)/k_B T}
 \end{aligned}$$

$$\begin{aligned}
 \text{Then, } E_F &= k_B T \ln \frac{n}{n_i} + E_i \\
 &\approx k_B T \ln \frac{10^{17}}{10^{10}} + E_i
 \end{aligned}$$

(Note: $k_B T \ln 10 \approx 60 \text{ meV}$)

$$E_F \approx E_i + 0.42 \text{ eV}$$

Does this make sense?



Roughly checks out!

d) $E_f - E_i < 0 \implies$ closer to VB

p-type

Use formula from before:

$$n = n_i e^{(E_f - E_i)/k_B T}$$

$$p = n_i e^{-(E_f - E_i)/k_B T}$$

\implies

$$n = 9.3 \times 10^4 \text{ cm}^{-3}$$
$$p \approx 1.07 \times 10^{15} \text{ cm}^{-3}$$

II) Drift Current

a) Recap of lecture:

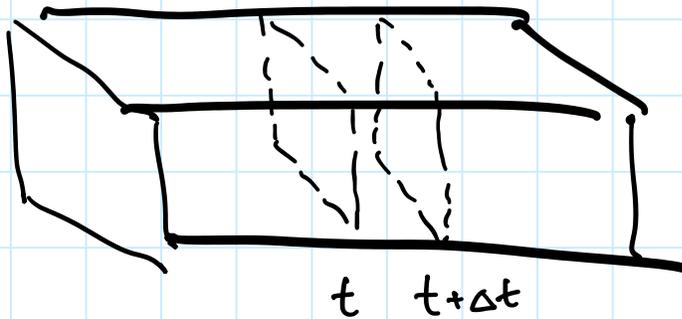
$$m \Delta v = \Delta p = F \tau \leftarrow \begin{array}{l} \text{mean time} \\ \text{to collision} \end{array}$$

$$\implies \Delta v = \frac{F \tau}{m^*} = \frac{q E \tau}{m^*} = \left(\frac{q \tau}{m^*} \right) E$$

Δv is the drift velocity v_d

$$\begin{aligned} v_{d,p} &= \mu_p E & v_{d,n} &= -\mu_n E \\ \mu_p &= q\tau / m_p^* & \mu_n &= q\tau / m_n^* \end{aligned}$$

To calculate drift current, simply count the number of charges going past a unit area per unit time



Charge flowing through surface in $(t, t+\Delta t)$ = charge per carrier \times # charges per unit vol \times vol in $t, t+\Delta t$

$$\Delta Q_n = -q n (A v_d \Delta t)$$

$$\Delta Q_p = q p (A v_d \Delta t)$$

$$j = \Delta Q / A \Delta t = I / A$$

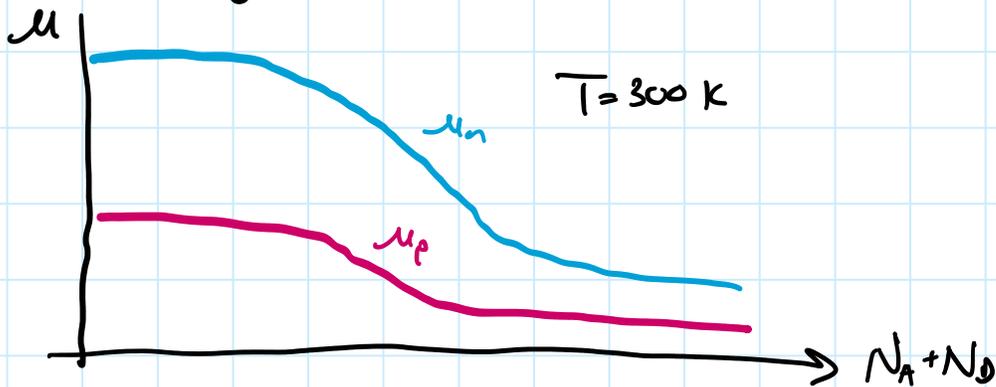
$$\Rightarrow j_n = -q n v_n = +q n \mu_n E$$

$$j_p = q p v_p = q p \mu_p E$$



$$\begin{aligned}
 \vec{j}_{\text{drift}} &= \vec{j}_n + \vec{j}_p \\
 &= (q n \mu_n + q p \mu_p) \vec{E} \\
 &= \sigma \vec{E} \\
 &\text{Ohm's Law}
 \end{aligned}$$

b) Mobility vs Dopant Concentration



Q: Why is the trend generally decreasing?

A: We can get a hint of what is happening from the x-axis, which is total impurity ion concentration.

Evidently, the phenomenon is due to the presence of dopants, more so than a net n or p-doping.

In fact, the phenomenon is impurity

In fact, the phenomenon is impurity ion scattering: the Coulombic force from the charged impurity ions causes many charges to change direction, and naturally this gets worse (τ decreases) as more ions are added.



Q: Why is the trend initially flat?

A: This should give a hint that some other effect is

dominating in the low doping region.

This effect is phonon scattering — lattice vibrations from the finite crystal temperature are the dominant source of scattering in this regime. In fact,

$$\frac{1}{\mu} = \frac{1}{\mu_{\text{phonon}}} + \frac{1}{\mu_{\text{ion}}}$$

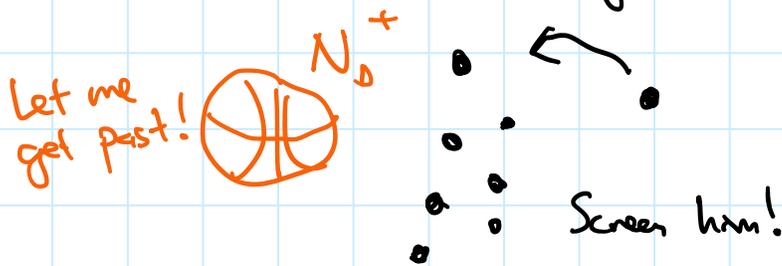
If $\mu_{phonon} \ll \mu_{ion}$, $\mu \approx \mu_{phonon}$

If $\mu_{ion} \ll \mu_{phonon}$, $\mu \approx \mu_{ion}$

Q: Why is the trend flat in the large dopant region?

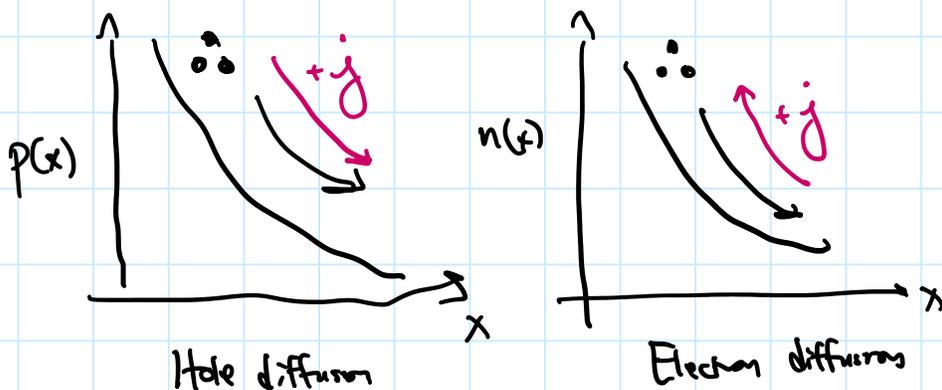
A: The scattering potential is partially "screened" by the carriers themselves.

Essentially, the carriers redistribute to cancel out some of the field.



III. Diffusion Current

a) Hole and electron diffusion



Expect $j_{hole} \propto -\frac{dp}{dx}$. Expect $j_{electron} \propto \frac{dn}{dx}$

Expect $j_{p,diff} \propto -\frac{dp}{dx}$; Expect $j_{n,diff} \propto \frac{dn}{dx}$

In fact,

$$\begin{aligned} j_{p,diff} &= -gD_p \frac{dp}{dx} \\ j_{n,diff} &= gD_n \frac{dn}{dx} \end{aligned}$$

Generalized version: Fick's first law

$$j = -D \frac{dp}{dx}$$

j : diffusion flux (amount of substance per unit area per unit time)

D : diffusivity

p : concentration (amount of substance per unit volume)

b) Einstein Relation

In equilibrium, diffusion and drift will balance each other (no net particle flow). Can show this leads to:

$$\frac{D_n}{\mu_n} = \frac{k_B T}{q}$$

(and similarly for holes)

This is a very profound result. A transport coefficient D_n is related to a dissipative process (scattering $\rightarrow \mu_n$) through thermal fluctuations $k_B T$.

This is an example of the fluctuation - dissipation theorem.

Another example might be drag, whose counterpart is Brownian motion. The

Einstein relation would then be:

$$\overset{\text{diffusivity}}{\uparrow} \frac{D}{\gamma} = k_B T \leftarrow \text{thermal fluctuations}$$

\downarrow
viscosity